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FIG.1

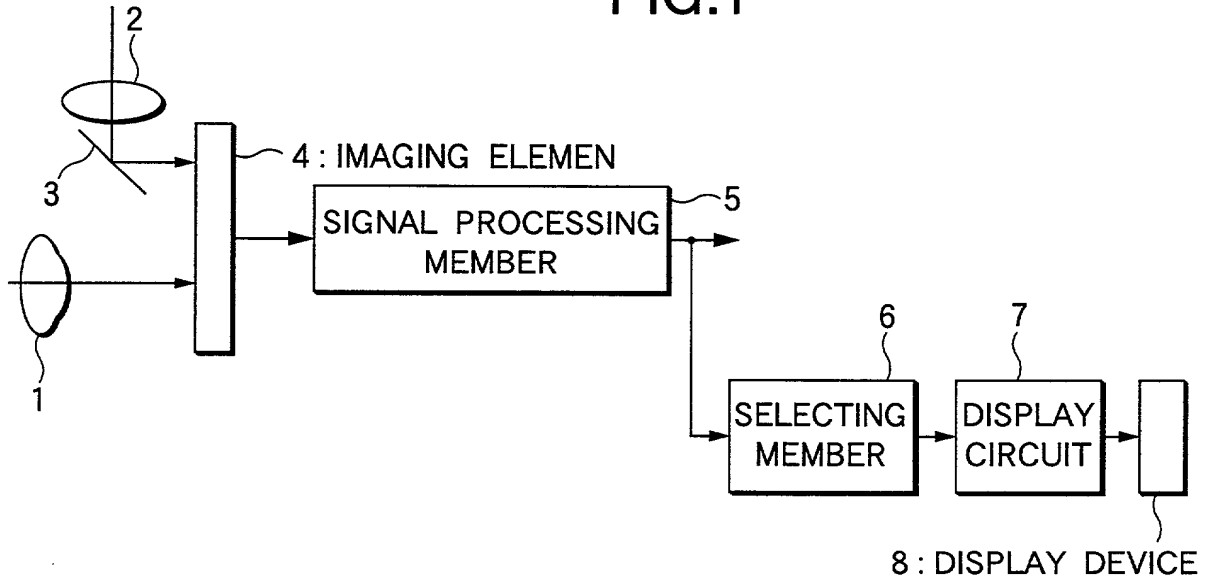
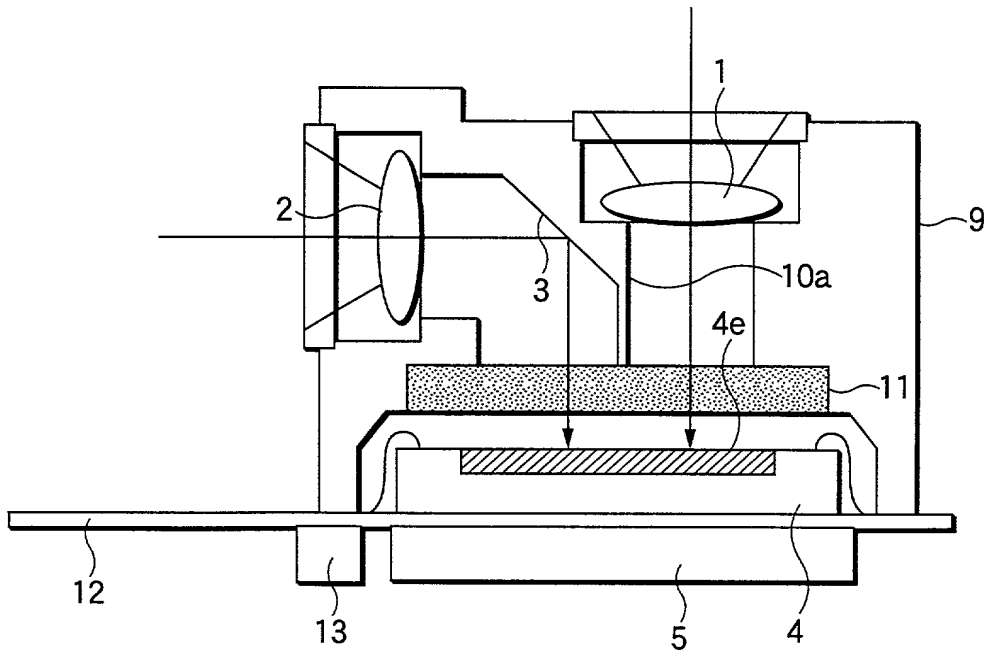


FIG.2



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FIG.3

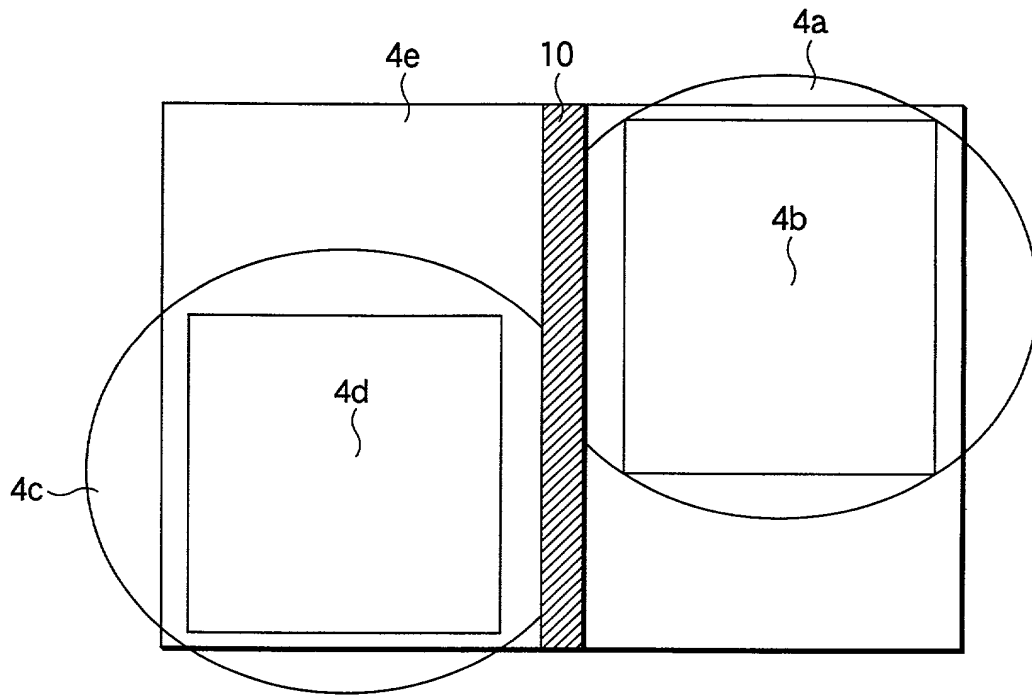
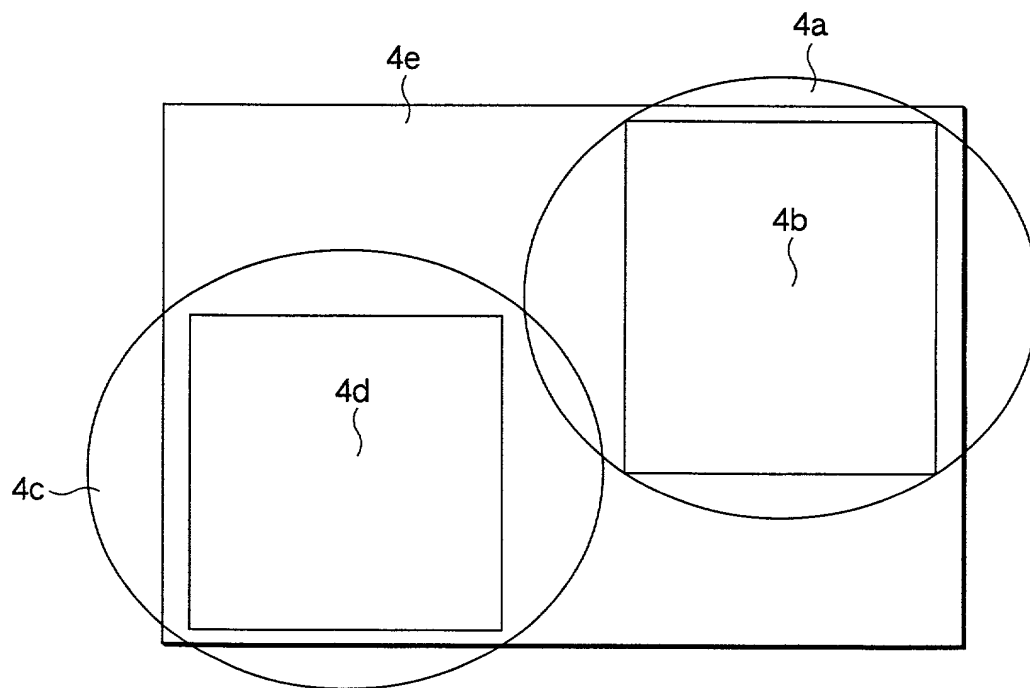
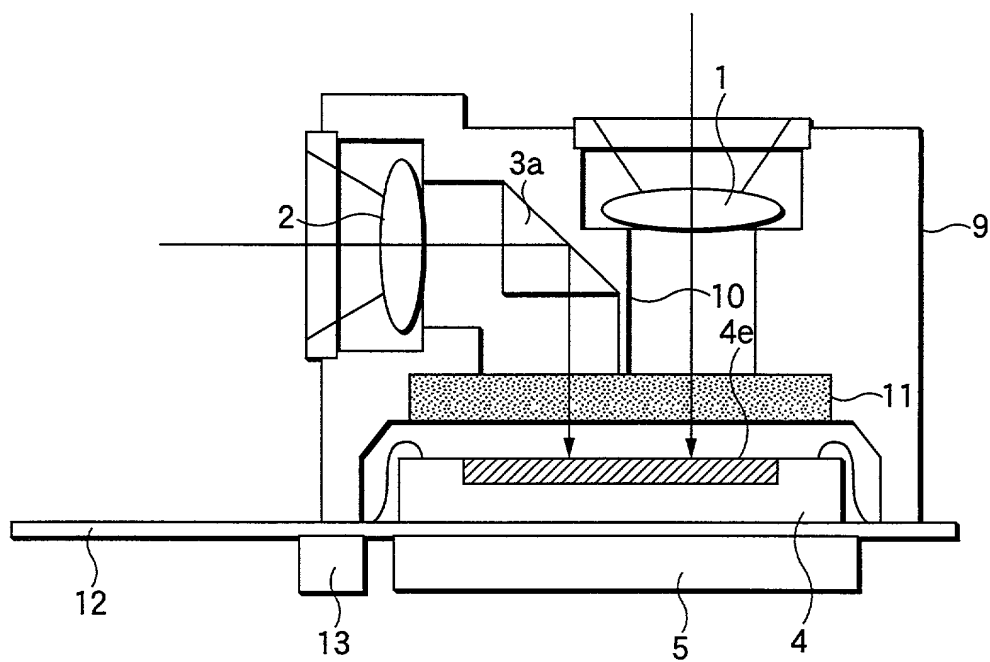


FIG.4



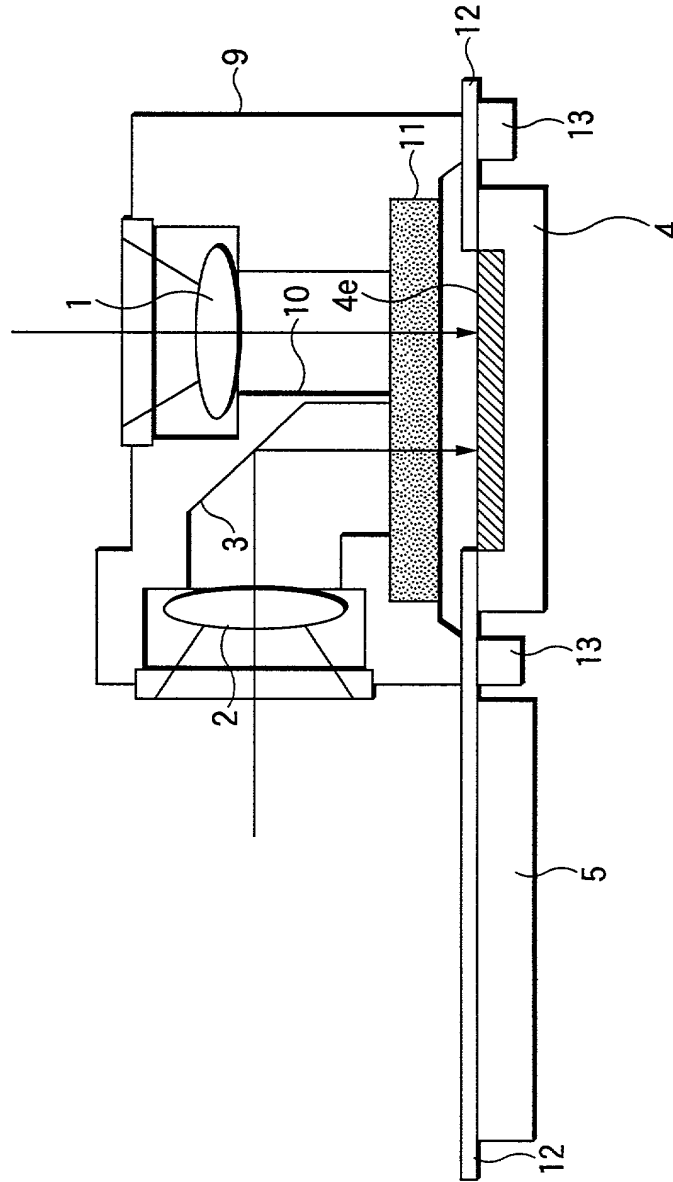
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FIG.5



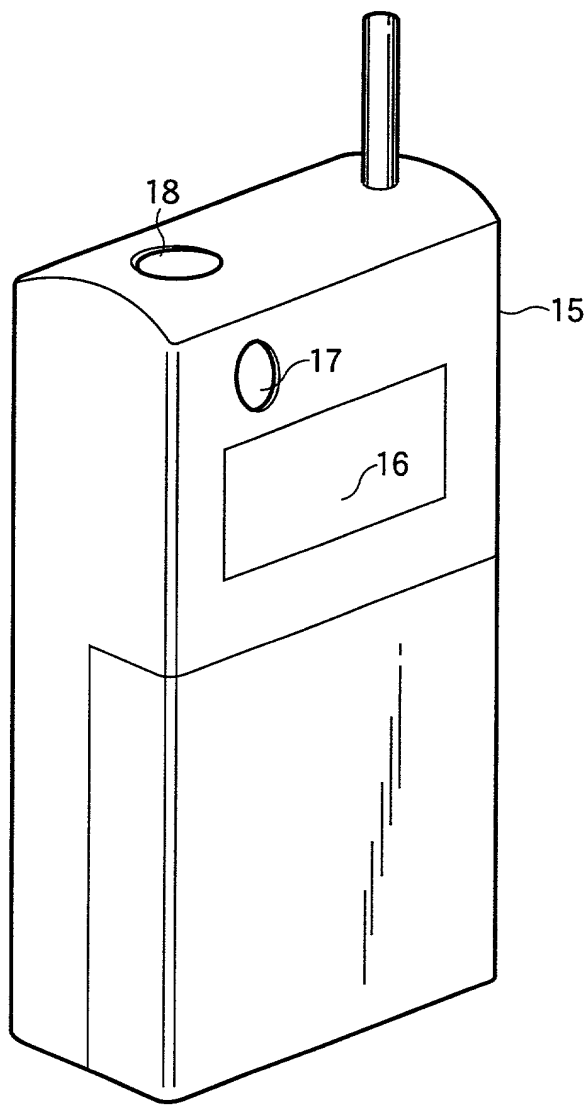
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FIG.6



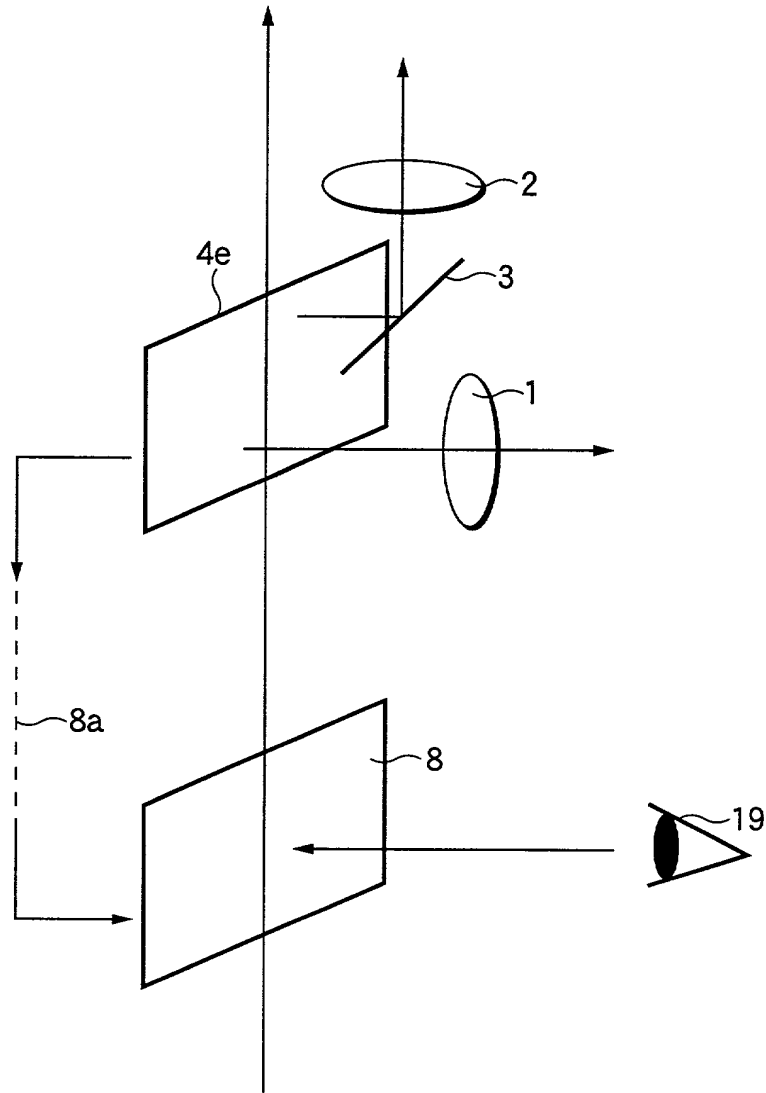
The diagram illustrates a cross-sectional view of a measurement apparatus. A light source (2) emits a beam (3) through a lens (1) onto a sample (10). The sample is placed on a substrate (4) with a thin film (4e) on top. The substrate is supported by a base (5) and a frame (9). A detector (11) is positioned to receive light reflected from the sample. A scale (12) and a support (13) are also shown.

FIG.8



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FIG.9



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FIG.10A

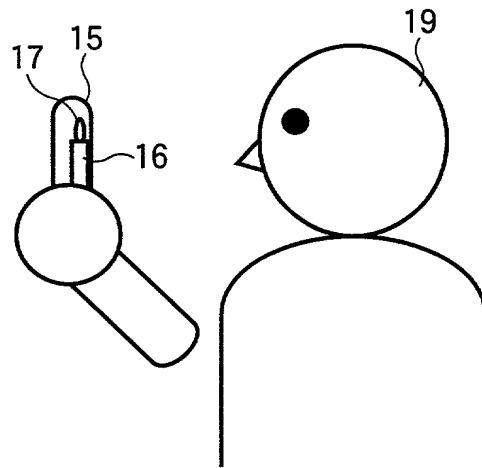


FIG.10B

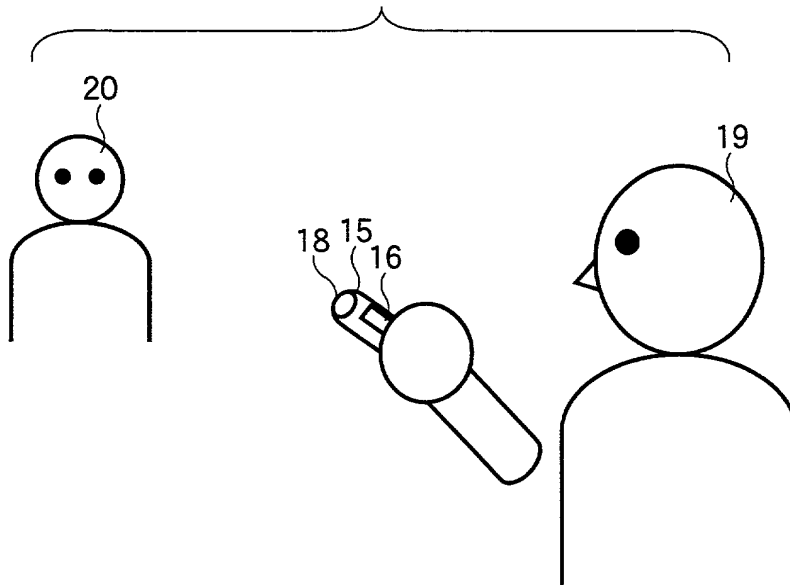


FIG. 10A



FIG.11

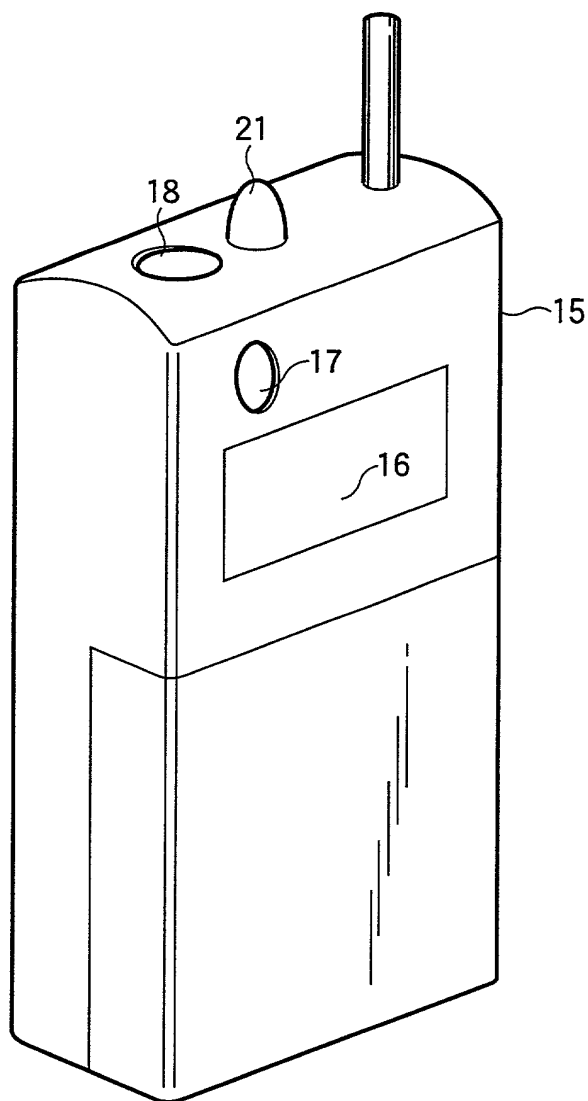
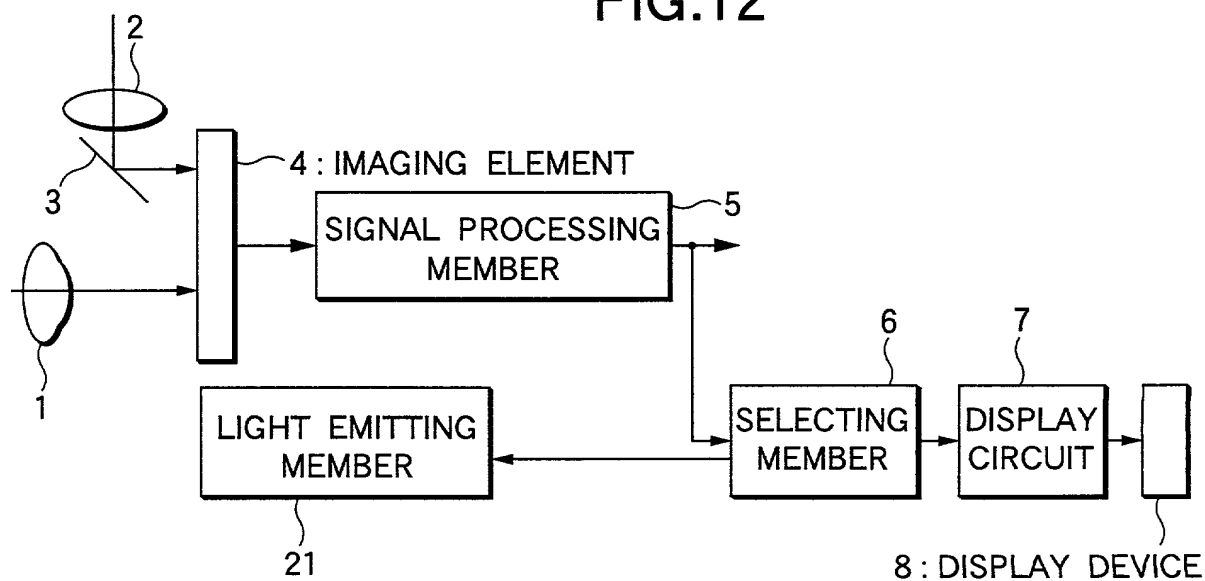


FIG.12



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FIG.13A

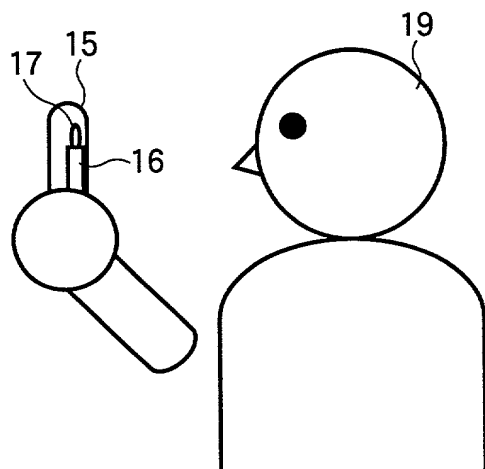
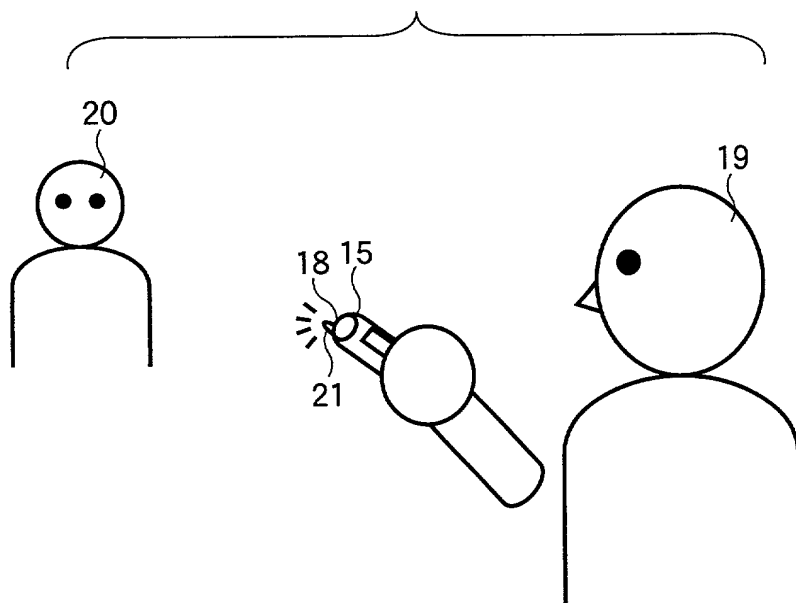
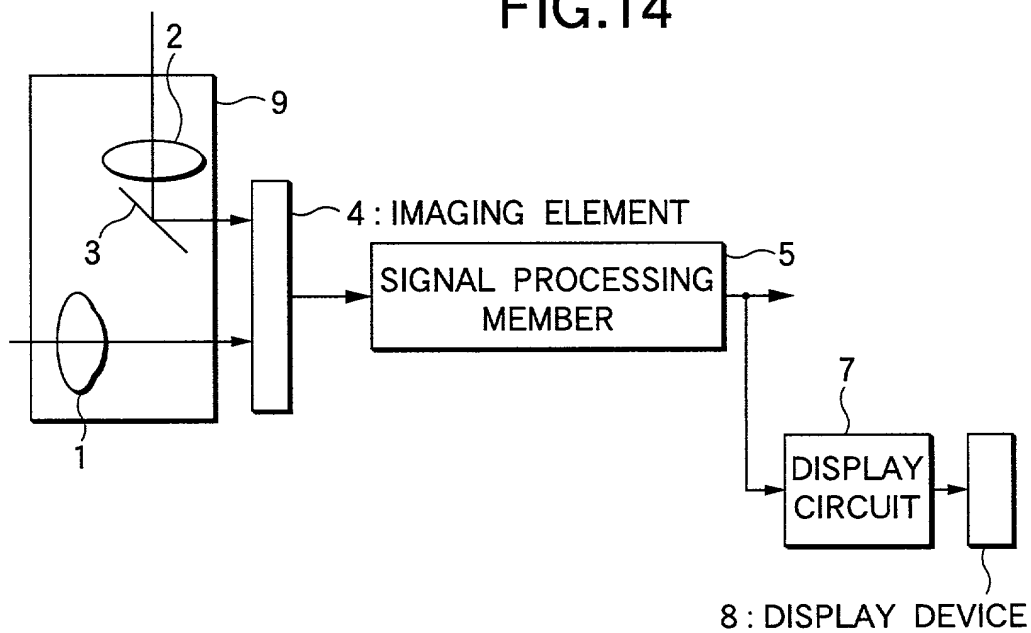


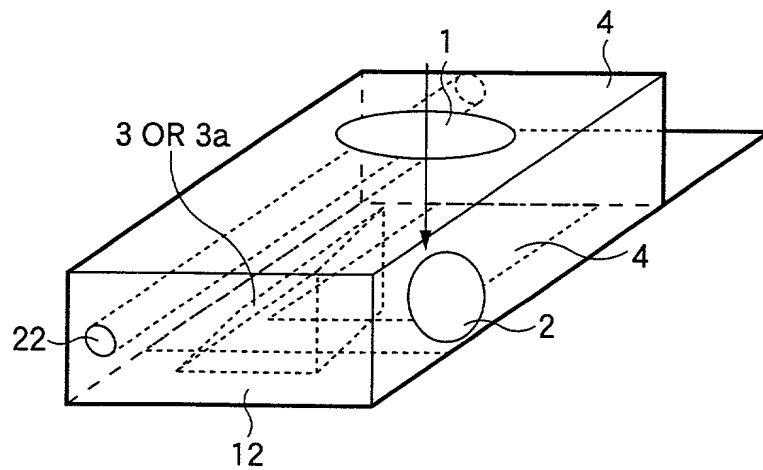
FIG.13B



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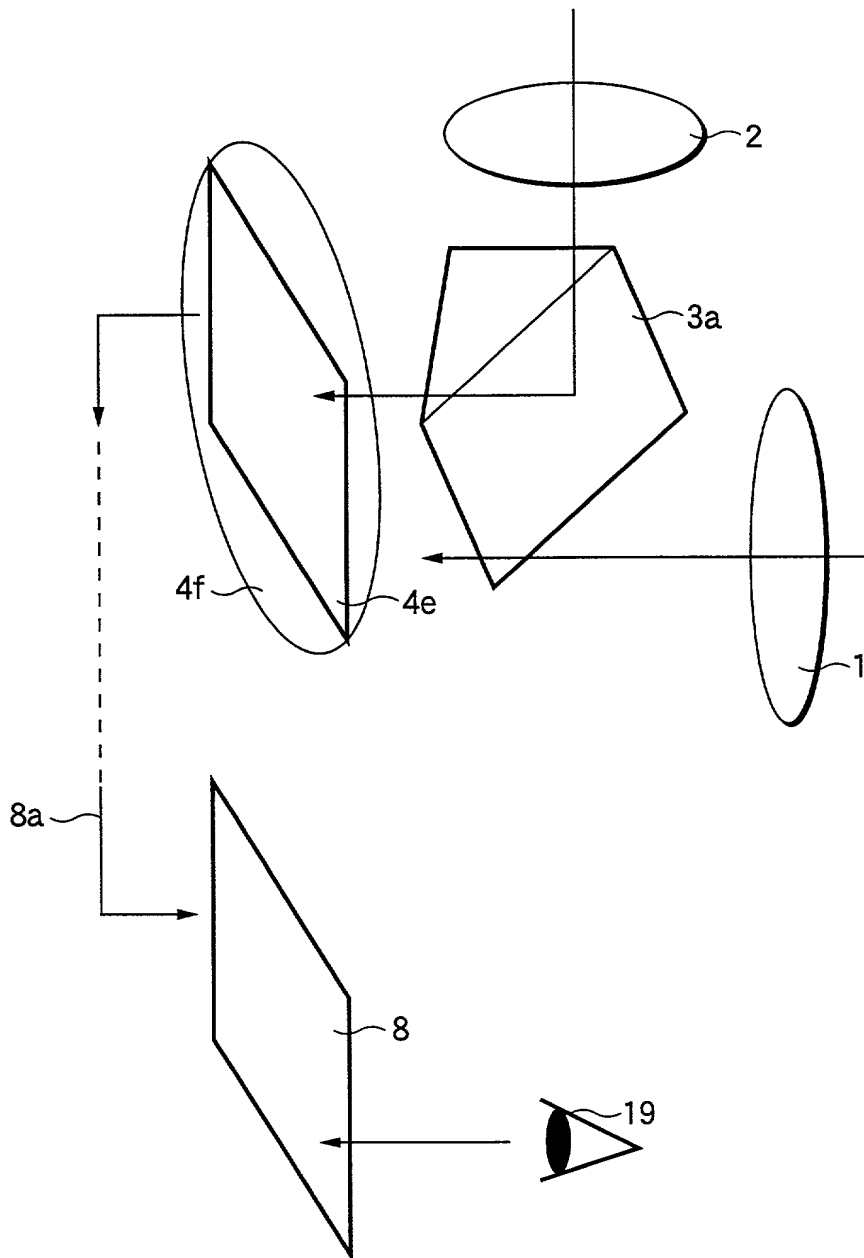
FIG.14





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FIG.16



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FIG.17

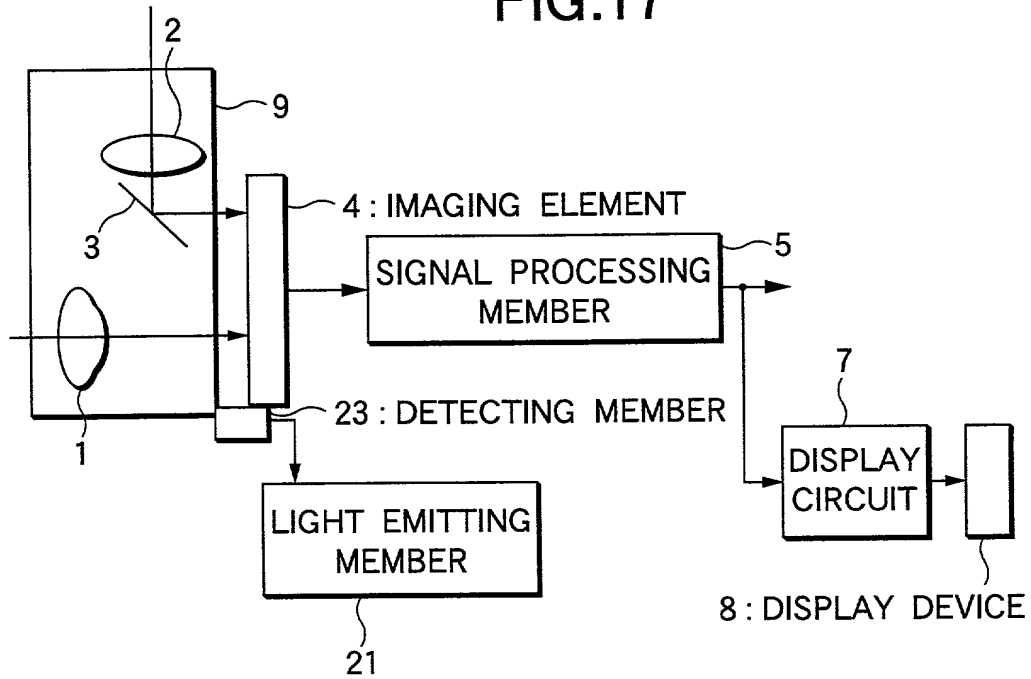
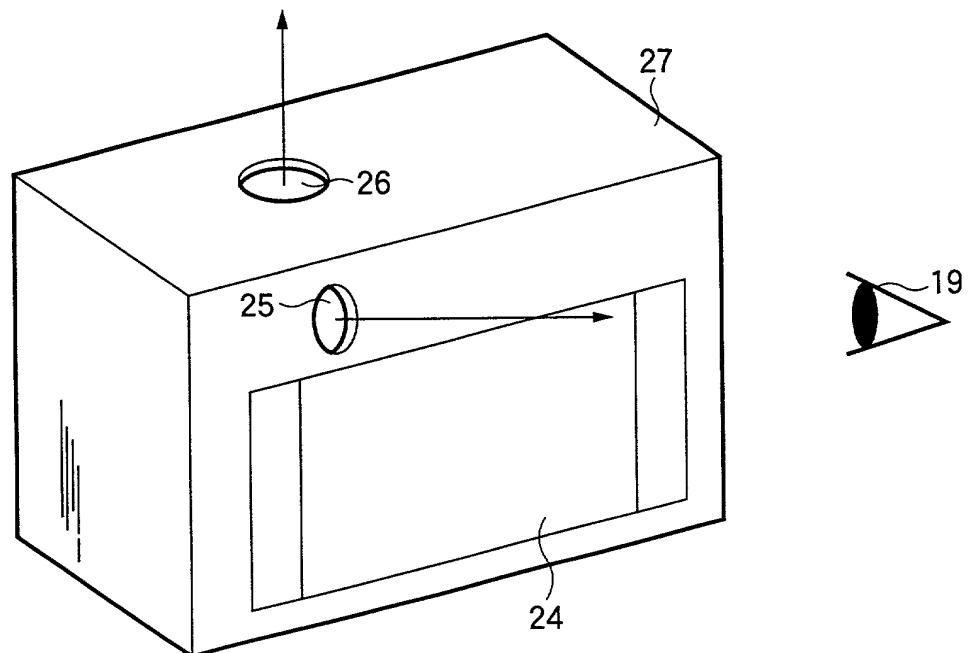


FIG.18



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FIG.19A

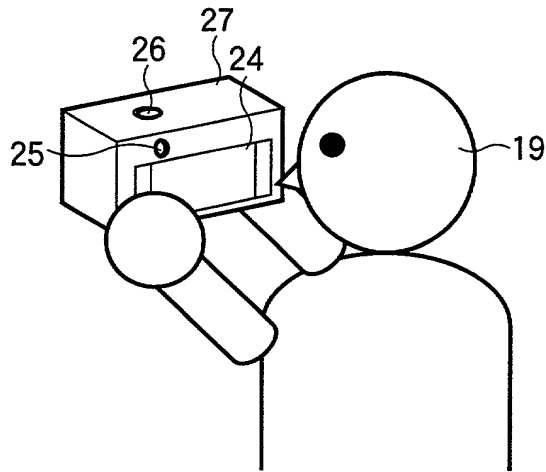


FIG.19B

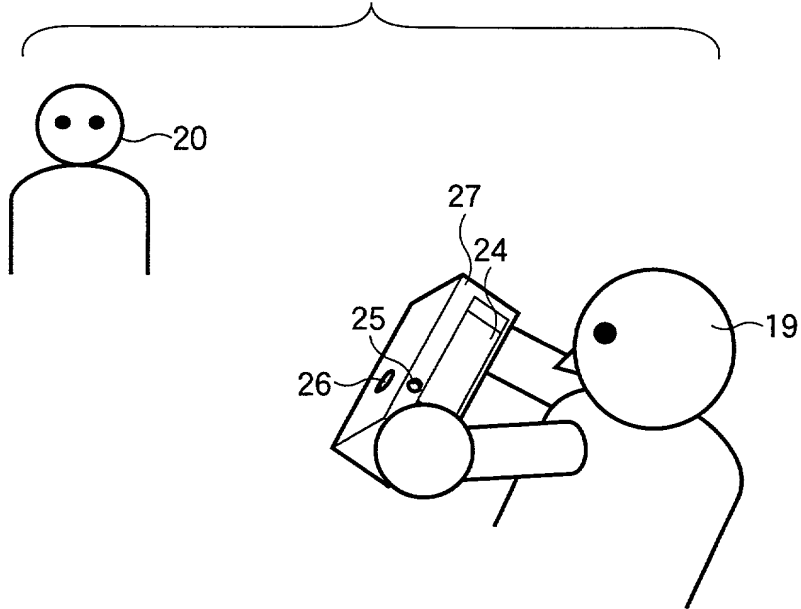




FIG.20A

FRONT VIEW

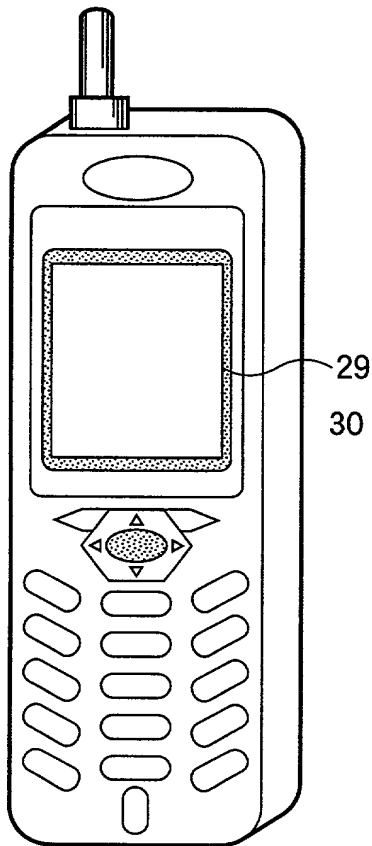


FIG.20B

REAR VIEW

